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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Young Hoon Kwark

Examiner: Emily Chan

Serial No: 10/769,115

Group Art Unit: 2829

Filed: January 30, 2004

Docket: YOR920030625US1 (163-27)

For: CONTACTLESS CIRCUIT TESTING FOR ADAPTIVE WAFER PROCESSING

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

RESPONSE TO OFFICE ACTION

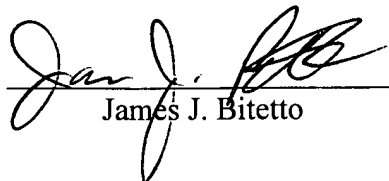
SETTING FORTH A RESTRICTION REQUIREMENT

Sir:

In response to the Office Action mailed May 23, 2005, Applicants hereby elect to prosecute the claims directed to Group I drawn to a system for measuring circuits on an integrated circuit substrate, i.e., claims 1-19. Applicants make the present election with traverse.

CERTIFICATE OF MAILING 37 C.F.R. §1.8(a)

I hereby certify that this correspondence (and any document referred to as being attached or enclosed) is being deposited with the United States Postal Service as first class mail, postage paid in an envelope addressed to: Mail Stop Amendment, Commissioner for Patents, P. O. Box 1450, Alexandria, VA 22313-1450
20231 on 6/22/05.


James J. Bitetto